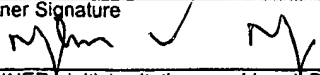


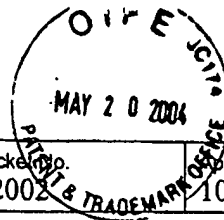
Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-092002	Application No. 10/718,584
	Applicant Shunpei Yamazaki et al.		
	Filing Date November 24, 2003	Group Art Unit 2811	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
M	AA	5,990,998	11/23/1999	Park et al.			04/10/1997
	AB						
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
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	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
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Examiner Signature 	Date Considered 5-25-05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
12732-092002Application No.
10/718,584**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Shunpei Yamazaki et al.Filing Date
November 24, 2003Group Art Unit
2811**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
nm	AL	0 082 012 A2	06/22/1983	EUROPE	<u> </u>	<u> </u>	In English	
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
nm	AQ	Australian Patent Office Search Report (Application No. SG 200200805-0), 8 pages
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

5-25-05

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-092002	Application No. New Divisional
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date November 24, 2003	Group Art Unit Unknown

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
NW	AA	US 2002/0110941 A1	08/15/2002	Yamazaki et al.			01/26/2001
	AB	US 2002/0070382 A1	06/13/2002	Yamazaki et al.			12/11/2001
	AC	US 2001/0055841 A1	12/27/2001	Yamazaki et al.			04/12/2001
	AD	US 2001/0052950 A1	12/20/2001	Yamazaki et al.			03/16/2001
	AE	US 2001/0049197 A1	12/06/2001	Yamazaki et al.			06/04/2001
	AF	US 2001/0030322 A1	10/18/2001	Yamazaki et al.			02/02/2001
	AG	US 2002/0017685 A1	02/14/2002	Kasahara et al.			05/03/2001
	AH	US 2002/0016028 A1	02/07/2002	Arao et al.			06/05/2001
	AI	US 2002/0013022 A1	01/31/2002	Yamazaki et al.			05/09/2001
	AJ	US 2002/0006705 A1	01/17/2002	Suzawa et al.			05/10/2001
	AK	6,031,290	02/29/2000	Miyazaki et al.			03/13/1998
	AL	6,365,917	04/02/2002	Yamazaki			11/16/1999
	AM	6,448,578	09/2002	Shimada et al.			
	AN	6,475,836	11/05/2002	Suzawa et al.			03/28/2000
NW	AO	6,515,336	02/04/2003	Suzawa et al.			09/18/2000

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
NW	AP	6-148685	05/27/1994	Japan			Full	
NW	AQ	7-235680	09/05/1995	Japan			Full	
NW	AR	8-274336	10/18/1996	Japan			Full	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AS	
	AT	
	AU	
	AV	

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Sheet 1 of 1

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-092002	Application No. 10/718,584
	Applicant Shunpei Yamazaki et al.		
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>W</i>	AA	2002/0106861 A1	08/08/2002	Yamazaki	1	1	04/05/2002
<i>W</i>	AB	6,399,454 B1	06/04/2002	Yamazaki	1	1	07/13/1998
	AC						
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	AG						
	AH						
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	AJ						
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U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
W	AA	3,108,914	10/29/1963	Hoerni			—
	AB	3,791,883	02/12/1974	Takei et al.			—
	AC	4,309,224	01/05/1982	Shibata			—
	AD	4,330,363	05/18/1982	Biegesen et al.			—
	AE	4,502,204	03/05/1985	Togashi et al.			—
	AF	4,727,044	02/23/1988	Yamazaki			—
	AG	4,851,363	07/25/1989	Troxell et al.			—
	AH	4,915,772	04/10/1990	Fehlner et al.			—
	AI	5,075,259	12/24/1991	Moran			—
	AJ	5,108,843	04/28/1992	Ohtaka et al.			—
	AK	5,147,826	09/15/1992	Liu et al.			—
	AL	5,219,786	06/15/1993	Noguchi			—
	AM	5,244,836	09/14/1993	Lim			—
	AN	5,248,630	09/28/1993	Serikawa et al.			—
	AO	5,273,920	12/28/1993	Kwasnick et al.			—
	AP	5,278,093	01/11/1994	Yonehara			—
	AQ	5,289,030	02/22/1994	Yamazaki et al.			—
	AR	5,311,041	05/10/1994	Tomimaga et al.			—
	AS	5,352,291	10/04/1994	Zhang et al.			—
	AT	5,387,530	02/07/1995	Doyle et al.			—
	AU	5,403,772	04/04/1995	Zhang et al.			—
	AV	5,426,064	06/20/1995	Zhang et al.			—
	AW	5,481,121	01/02/1996	Zhang et al.			—
	AX	5,529,937	06/25/1996	Zhang et al.			—
	AY	5,605,846	02/25/1997	Ohtani et al.			—
	AZ	5,639,698	06/17/1997	Yamazaki et al.			—
W	AAA	5,710,050	01/20/1998	Makita et al.			—


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	Applicant Shunpei Yamazaki et al.		
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
W	ABB	5,773,327	06/30/1998	Yamazaki et al.			
	ACC	5,843,225	12/01/1998	Takayama et al.			
	ADD	6,168,981 B1	01/02/2001	Battaglia et al.			
	AEE	6,287,988 B1	09/11/2001	Nagamine et al.			
	AFF	6,436,745 B1	08/20/2002	Gotou et al.			
	AGG	US 2002/0164843 (with current claims)	11/07/2002	Yamazaki et al.			
W	AHH	US 2003/0060057	03/27/2003	Raaijmakers et al.			

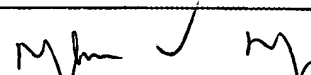
Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
W	AII	JP 04-011722	01/16/1992	Japan			Full	
	AJJ	JP 06-013610	01/21/1994	Japan			Abs	
	AKK	JP 06-267978	09/22/1994	Japan			Abs	
	ALL	JP 56-024925	03/10/1981	Japan			Abs	
W	AMM	JP 60-105216	06/10/1985	Japan			Abs	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
W	ANN	S. Caune et al.; "Combined CW Laser and Furnace Annealing of Amorphous Si and Ge in Contact with some Metals"; <u>Applied Surface Science</u> , vol. 36, pp. 597-604 (1989)
	AOO	B.C. Ahn et al.; "Batch-Processing of High-Performance Amorphous-Silicon/Silicon-Nitride Thin-Film Transistors" <u>IEEE Display Research Conference</u> , pp. 85-88 (1991)
	APP	Kenji Sera et al.; "High-Performance TFT's Fabricated by XeCl Excimer Laser Annealing of Hydrogenated Amorphous-Silicon Film"; <u>IEEE Transactions On Electron Device</u> , vol. 36, no. 12; pp. 2868-2872 (December 1989)
	AQQ	L. Hultman et al.; "Crystallization of Amorphous Silicon During Thin-film Gold Reaction"; <u>J. Appl. Phys.</u> , vol. 62, no. 9; pp. 3647-3655 (November 1987)
W	ARR	Yunosuke Kawazu et al.; "Low-Temperature Crystallization of Hydrogenated Amorphous Silicon Induced by Nickel Silicide Formation"; <u>Japanese Journal of Applied Physics</u> , vol. 29, no. 12; pp. 2698-2704 (1990)

Examiner Signature 	Date Considered 5-25-05
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Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Shunpei Yamazaki et al.	
		Filing Date November 24, 2003	Group Art Unit 2811
(37 CFR §1.98(b))			

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
W	ASS	M. Fuse et al.; "Performance of Poly-Si Thin Film Transistors Fabricated by Excimer-Laser Annealing of SiH ₄ - and Si ₂ H ₆ - Source Low Pressure Vapor Deposited a-Si Films with or without Solid-Phase Crystallization"; <u>Solid State Phenomena</u> , vols. 37-38; pp. 565-570 (1994)
I	ATT	Rafael Reif et al.; "Plasma-Enhanced Chemical Vapor Deposition"; <u>Thin Film Processes II</u> ; pp. 537-541; (1991)
I	AUU	Sorab Ghandhi.; "Thermal Oxidation of Gallium Arsenide"; <u>VLSI Fabrication Principles - Silicon and Gallium Arsenide</u> ; 2 nd Edition, pp. 484, 485, 533-535
	AVV	S.M. Sze; <u>VLSI Technology</u> ; 2 nd Edition, pp. 85-86, 266-267 (1988)
W	AWW	Hongyong Zhang et al.; "KrF Excimer Laser Annealed TFT with Very High Field-Effect Mobility of 329 cm ² /v · s"; <u>IEEE Electron Device Letters</u> ; vol. 13, no. 5; pp. 297-299 (May 1992)

Examiner Signature 	Date Considered 8-25-05
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